

PROCEEDINGS OF SPIE

Photonic Instrumentation Engineering VI

Yakov G. Soskind
Editor

5–7 February 2019
San Francisco, California, United States

Sponsored and Published by
SPIE

Volume 10925

Proceedings of SPIE 0277-786X, V. 10925

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Photonic Instrumentation Engineering VI, edited by Yakov G. Soskind,
Proc. of SPIE Vol. 10925, 1092501 · © 2019 SPIE · CCC code:
0277-786X/19/\$18 · doi: 10.1117/12.2531363

Proc. of SPIE Vol. 10925 1092501-1

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Author(s), "Title of Paper," in *Photonic Instrumentation Engineering VI*, edited by Yakov G. Soskind
Proceedings of SPIE Vol. 10925 (SPIE, Bellingham, WA, 2019) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510624924
ISBN: 9781510624931 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org

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